Application/Control No.	Applicant(s)/Patent under Reexamination	
10/517,114	TANG ET AL.	
Examiner	Art Unit	
TUAN A. PHAM	2618	

SEARCHED					
Class	Subclass	Date	Examiner		
455	424	6/30/2006	РНАМ		
	425				
	452.1				
	456.5				
	456.6	6/30/2006	PHAM		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	1	<u></u>		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
		